



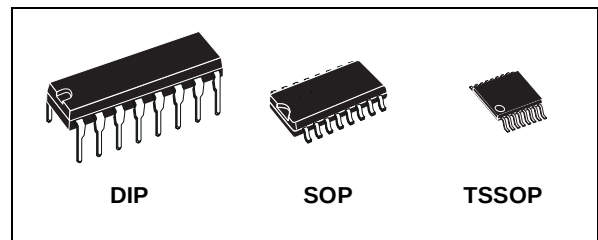
M74HC133

13 INPUT NAND GATE

- HIGH SPEED :
 $t_{PD} = 14 \text{ ns (TYP.)}$ at $V_{CC} = 6V$
- LOW POWER DISSIPATION:
 $I_{CC} = 1\mu A(\text{MAX.})$ at $T_A = 25^\circ C$
- HIGH NOISE IMMUNITY:
 $V_{NIH} = V_{NIL} = 28 \% V_{CC} (\text{MIN.})$
- SYMMETRICAL OUTPUT IMPEDANCE:
 $|I_{OH}| = I_{OL} = 4mA (\text{MIN})$
- BALANCED PROPAGATION DELAYS:
 $t_{PLH} \cong t_{PHL}$
- WIDE OPERATING VOLTAGE RANGE:
 $V_{CC} (\text{OPR}) = 2V \text{ to } 6V$
- PIN AND FUNCTION COMPATIBLE WITH
 74 SERIES 133

DESCRIPTION

The M74HC133 is an high speed CMOS 13-INPUT NAND GATE fabricated with silicon gate C²MOS technology. The internal circuit is composed of 7 stages including buffer output, which enables high noise immunity and stable output.

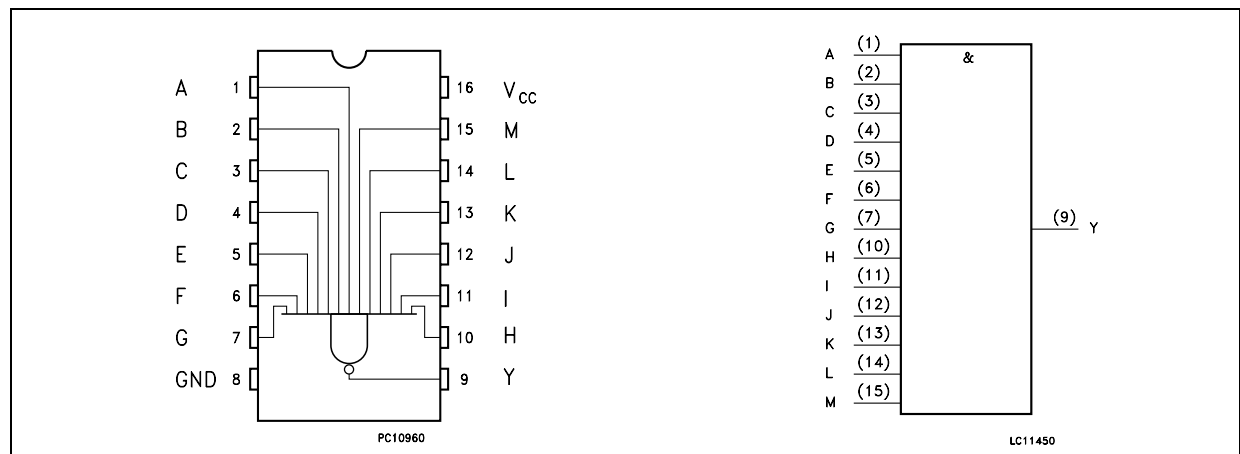


ORDER CODES

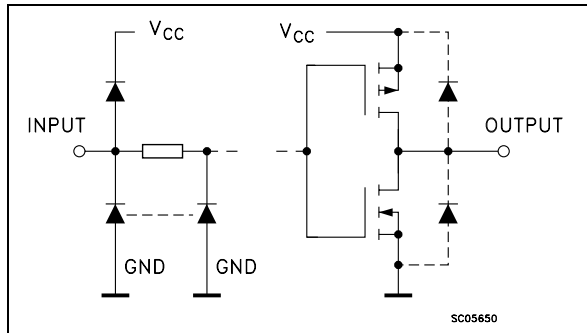
PACKAGE	TUBE	T & R
DIP	M74HC133B1R	
SOP	M74HC133M1R	M74HC133RM13TR
TSSOP		M74HC133TTR

All inputs are equipped with protection circuits against static discharge and transient excess voltage.

PIN CONNECTION AND IEC LOGIC SYMBOLS



INPUT AND OUTPUT EQUIVALENT CIRCUIT



PIN DESCRIPTION

PIN No	SYMBOL	NAME AND FUNCTION
1 to 7, 10 to 15	A to G, H to M	Data Inputs
9	Y	Data Output
8	GND	Ground (0V)
16	Vcc	Positive Supply Voltage

TRUTH TABLE

A	B	C	D	E	F	G	H	I	J	K	L	M	Y
L	X	X	X	X	X	X	X	X	X	X	X	X	H
X	L	X	X	X	X	X	X	X	X	X	X	X	H
X	X	L	X	X	X	X	X	X	X	X	X	X	H
X	X	X	L	X	X	X	X	X	X	X	X	X	H
X	X	X	X	L	X	X	X	X	X	X	X	X	H
X	X	X	X	X	L	X	X	X	X	X	X	X	H
X	X	X	X	X	X	L	X	X	X	X	X	X	H
X	X	X	X	X	X	X	L	X	X	X	X	X	H
X	X	X	X	X	X	X	X	L	X	X	X	X	H
X	X	X	X	X	X	X	X	X	L	X	X	X	H
X	X	X	X	X	X	X	X	X	X	L	X	X	H
X	X	X	X	X	X	X	X	X	X	X	L	X	H
X	X	X	X	X	X	X	X	X	X	X	X	L	H
H	H	H	H	H	H	H	H	H	H	H	H	H	L

X : Don't Care

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V_{CC}	Supply Voltage	-0.5 to +7	V
V_I	DC Input Voltage	-0.5 to $V_{CC} + 0.5$	V
V_O	DC Output Voltage	-0.5 to $V_{CC} + 0.5$	V
I_{IK}	DC Input Diode Current	± 20	mA
I_{OK}	DC Output Diode Current	± 20	mA
I_O	DC Output Current	± 25	mA
I_{CC} or I_{GND}	DC V_{CC} or Ground Current	± 50	mA
P_D	Power Dissipation	500(*)	mW
T_{stg}	Storage Temperature	-65 to +150	°C
T_L	Lead Temperature (10 sec)	300	°C

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied

(*) 500mW at 65 °C; derate to 300mW by 10mW/°C from 65°C to 85°C

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter		Value	Unit
V _{CC}	Supply Voltage		2 to 6	V
V _I	Input Voltage		0 to V _{CC}	V
V _O	Output Voltage		0 to V _{CC}	V
T _{op}	Operating Temperature		-55 to 125	°C
t _r , t _f	Input Rise and Fall Time	V _{CC} = 2.0V	0 to 1000	ns
		V _{CC} = 4.5V	0 to 500	ns
		V _{CC} = 6.0V	0 to 400	ns

DC SPECIFICATIONS

Symbol	Parameter	Test Condition		Value							Unit
		V _{CC} (V)		T _A = 25°C			-40 to 85°C		-55 to 125°C		
				Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
V _{IH}	High Level Input Voltage	2.0		1.5			1.5		1.5		V
		4.5		3.15		3.15		3.15			
		6.0		4.2		4.2		4.2			
V _{IL}	Low Level Input Voltage	2.0				0.5		0.5		0.5	V
		4.5				1.35		1.35		1.35	
		6.0				1.8		1.8		1.8	
V _{OH}	High Level Output Voltage	2.0	I _O =-20 μA	1.9	2.0		1.9		1.9		V
		4.5	I _O =-20 μA	4.4	4.5		4.4		4.4		
		6.0	I _O =-20 μA	5.9	6.0		5.9		5.9		
		4.5	I _O =-4.0 mA	4.18	4.31		4.13		4.10		
		6.0	I _O =-5.2 mA	5.68	5.8		5.63		5.60		
V _{OL}	Low Level Output Voltage	2.0	I _O =20 μA		0.0	0.1		0.1		0.1	V
		4.5	I _O =20 μA		0.0	0.1		0.1		0.1	
		6.0	I _O =20 μA		0.0	0.1		0.1		0.1	
		4.5	I _O =4.0 mA		0.17	0.26		0.33		0.40	
		6.0	I _O =5.2 mA		0.18	0.26		0.33		0.40	
I _I	Input Leakage Current	6.0	V _I = V _{CC} or GND			± 0.1		± 1		± 1	μA
I _{CC}	Quiescent Supply Current	6.0	V _I = V _{CC} or GND			1		10		20	μA